**IBIS Open Forum Minutes**

Meeting Date: **November 20, 2014**

Meeting Location: **Yokohama, Japan**

**VOTING MEMBERS AND 2014 PARTICIPANTS**

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VIA Terence Hsieh, Justin Hsu

Via CPU Leon Liang

Vitesse Siris Tsang

Wadow Kazuhiko Kusunoki\*

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Wiwynn Corp. Scott CH Lee, Kevin TK Wang

Xpeedic Technology Wenliang Dia, Feng Ling, Zhouxiang Su

Yamanashi Avionics Co. Yasunori Yamashita\*

Zhejiang Uniview Technologies Fei Ye, Feng Ye

In the list above, attendees at the meeting are indicated by \*. Principal members or other active members who have not attended are in parentheses. Participants who no longer are in the organization are in square brackets.

**UPCOMING MEETINGS**

The bridge numbers for future IBIS teleconferences are as follows:

Date Meeting Number Meeting Password

December 5, 2014 205 475 958 IBIS

For teleconference dial-in information, use the password at the following website:

<https://ciscosales.webex.com/ciscosales/j.php?J=205475958>

All teleconference meetings are 8:00 a.m. to 9:55 a.m. US Pacific Time. Meeting agendas are typically distributed seven days before each Open Forum. Minutes are typically distributed within seven days of the corresponding meeting. When calling into the meeting, follow the prompts to enter the meeting ID. For new, local international dial-in numbers, please reference the bridge numbers provided by Cisco Systems at the following link:

<http://www.cisco.com/web/about/doing_business/conferencing/index.html>

NOTE: "AR" = Action Required.

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**WELCOME AND kEYNOTE COMMENTS**

The IBIS Open Forum summit was held in Yokohama, Japan, co-located with the Electronics Design Solutions Fair (EDS Fair) at the Pacifico Yokohama Conference Center. Approximately 111 people representing 69 organizations attended.

The statements below summarize the material presented. More details are available through the summit presentations posted online at:

<http://www.eda.org/ibis/summits/nov14c/>

Lance Wang opened the Summit. Shogo Fujimori (Fujitsu Advanced Technology and JEITA IBIS Promotion Working Group Chair) provided introductions and welcomes.

Lance continued by thanking the co-sponsors: the major sponsors JEITA and the IBIS Open Forum and also the co-sponsors ANSYS, Cadence Design Systems, Cybernet Systems, Mentor Graphics, MoDeCH and Zuken.

**ACTIVITIES AND DIRECTION OF IBIS**

Michael Mirmak (Intel Corporation, USA)

[Presented by Lance Wang (IO Methodology, USA)]

Lance Wang began by noting that the current version of IBIS is IBIS 6.0, and a parser, IBISCHK6, was released in June 2014. A user’s guide for IBISCHK6 is in development from the IBIS Quality task group and a work-in-progress document is available for review. An IBIS model review service is also available. As of today, three approved BIRDs propose major changes to IBIS 6.0, while five other approved BIRDs make clarifications or corrections. Eleven other BIRDs are proposed but not approved, and these cover areas including backchannel adaptation for equalization, expanded package modeling capabilities, Touchstone support for AMI analog buffer models and parameter passing for External Circuits. A major revision of the IBIS Open Forum basic policies and procedures is also underway. Changes to the IBIS Open Forum charter will allow for greater involvement in votes and officer elections by membership companies worldwide.

**INTRODUCTION OF IBIS PROMOTION WORKING GROUP**

Shogo Fujimori (Fujitsu Advanced Technologies, Japan)

Shogo Fujimori began by introducing the Japan Electronics and Information Technology Industries Association (JEITA) and Electronic Commerce Center committee organization. He continued with a summary of the IBIS Quality Working Group’s progress from 2007 to June 2014. That WG developed processes for testing, verifying and distributing quality IBIS models. Shogo noted that the IBIS Promotion Working Group is new. Their objective is to promote the use of IBIS models in simulation. Their action plan is to review the IBIS specification, summarize which keywords should be used for target applications, provide guidance on which versions of IBIS models should be used for specific simulation cases, and look at IBIS model inconsistencies. Their proposed activities include supporting logistics for the IBIS Summit in Japan, promoting IBIS model utilization including providing IBIS-related information, defining IBIS simulation guidelines and maintaining the IBIS Quality WG results. Shogo concluded by inviting more participation in the IBIS Promotion WG.

**INCONSISTENCY OF EBD (ELECTRICAL bOARD DESCRIPTION) SPECIFICATION IN DDR3 DIMM**

Shogo Fujimori (Fujitsu Advanced Technologies, Japan)

Shogo Fujimori gave an overview of the Electrical Board Description (EBD) modeling in IBIS. He showed an example from the IBIS specification of syntax for a differential clock-type circuit including a series termination. He introduced some problems encountered with EBD modeling of DDR3 fly-by topology clock nets including differential termination and AC termination. For differential terminations, description styles are vendor dependent. He noted an EBD that commented that the capacitor termination must be added external to the EBD, but it is not clear how to do this. Until IBIS 5.0, series components could not connect two separate [Path Description]s. This was allowed in IBIS 5.1, but it may not be supported in all EDA tools yet. Another issue is that the IBIS Terminator model cannot define AC terminations connected to the power terminal. Shogo proposed adding a Rac/Cac type termination to the Terminator model that connects to the power terminal. He would also like to see an EBD section added to the IBIS Cookbook.

**IBIS PACKAGE MODEL (PAST, PRESENT, WHAT’S NEXT)**

Shinichi Maeda (KEI Systems, Japan)

Shinichi Maeda gave an overview of package modeling in IBIS beginning with IBIS 1.0 through IBIS 6.0. This included [Package], [Pin], [Package Model] and EBD. IBIS has also released other interconnect modeling specifications including ICM, Touchstone 2.0 and IBIS-ISS. Several BIRDs have yet to be approved that relate to improving package and interconnect modeling in IBIS.

**DIFFERENTIAL BUFFER USING IBIS MODELS FOR PDN SIMULATIONS**

Lance Wang (IO Methodology, USA)

Lance Wang presented a case study of differential pair buffers in Power Delivery Network (PDN) simulations. The IBIS specification does not indicate how to make an IBIS power aware model for true differential pair buffers. Lance used a 1.5V LVDS true-differential buffer with balanced pullup and pulldowns for his study. The buffer also had access to the power supply connections for both the positive and negative signal drivers. The simulation correlated well to the transistor model when the IBIS model was extracted from separate power supplies for each of the positive and negative pins. If one doesn’t have access to each buffer’s power pins separately, this creates a problem. For this model, one can get a combined ISSO curve by setting up both pullup and pulldown, then taking the average for each buffer. For [Composite Current] waveforms, one can take one rising edge and one falling edge curve at the same time for the differential pair and add the results together. The resulting model is not a perfect correlation to the transistor model, but the results are better than using an IBIS model without the power aware features.

**TRUE DIFFERENTIAL IBIS MODEL FOR SERDES ANALOG BUFFER**

Shivani Sharma, Tushar Malik and Taranjit Kukal (Cadence Design Systems, India)

[Presented by Morihiro Nakazato, (Cadence Design Systems, Japan)]

Morihiro Nakazato gave an overview of current differential buffer modeling techniques in IBIS. An alternative approach to S-parameter characterization was shown using standard IBIS tabular data formats along with series elements to model differential current. This extended the approach suggested in the IBIS cookbook suggesting modeling of differential current using series resistance. A modeling flow was shown for extraction of common and differential mode impedances. From the impedance at a specific frequency one can calculate series and common mode reactances and resistances. Depending on the sign the reactance could be inductive or capacitive. A parallel RL network is then modeled using the series model type. A parallel RC network is modeled using C\_comp and clamp I-V tables. The true differential model provides much better accuracy than a pseudo differential IBIS model for channel simulation in terms of jitter, eye opening and reflection losses.

**IBIS AMI VALIDATION**

Zilwan Mahmod and Anders Ekholm (Ericsson, Sweden)

[Presented by Zilwan Mahmod (Ericsson, Sweden)]

Zilwan Mahmod began by describing design goals he has with IBIS AMI analysis. IBIS AMI models must be validated, as correct and validated models are needed. Certification is the first step a model must go through to check that the model behavior is reasonable. Zilwan presented a long checklist of items to verify. To do active correlation, the PCB model in simulation must be adjusted to match the real channel characteristics as seen in measurements. S-parameters from measurement can be used in the correlation exercise, but the PCB models need to be adjusted for later use in post-layout simulation. TX active validation is feasible, but RX active validation is not, because measurements at the decision point are not possible.

Zilwan's experience shows that many models fail certification for various reasons such as syntax errors, run time errors, simulated DC levels that don't match measured DC levels, idealized analog models, etc.

**IBIS MODEL ENGINEERING APPLICATION POSSIBILITY**

Kazuhiko Kusunoki (Wadow, Japan)

Kazuhiko Kusunoki noted that IBIS models are good for SI simulation but wondered how useful they could be for PI and EMI simulation. IBIS models contain useful information such as V-T waveforms, I-V data, [Ramp] data and RLC package data. V-T waveforms can be very useful for EMI by doing an FFT and looking at the spectral content. IBIS models can be a useful datasheet for PI and EMI because they contain information not usually found in the device datasheet. Kazuhiko looked at a case study of using models to estimate EMI on a PCB. He started with a Chip Power Model (CPM) to represent current flow in the power supply for the die. With use of only the CPM, no EMI was seen from the signal trace on the PCB. With a signal current model based on the datasheet and using the CPM, the simulation result showed unrealistically high radiation. Using an ideal current model based on the I-V data in the IBIS model and the CPM did not show any high frequency content in the radiation. The most realistic results were obtained by generating a signal current model from the FFT of the current waveform from an SI simulation using the IBIS model.

**INTRODUCTION OF P2401 LSI-PACKAGE-BOARD STANDARD FORMAT**

Yoshinori Fukuba (Toshiba Semiconductor & Storage, Japan)

Yoshinori Fukuba opened his presentation by stating that IEEE P2401 work started earlier this year, with working group membership being entity-based, for advanced IEEE Standards Association members. Several Japanese companies are currently represented in the working group. The group was formed because sometimes LSI (large-scale integrated circuits), package, and board designers work independently, but coordination of their work is needed. The industry generally wants to have a shared format for exchanging information in these areas, to shorten design and production cycles. Product development phases are long, and sometimes miss market windows. Having IBIS model simulations at each stage is desirable, but simulations take more time at each stage as development progresses. Simulation under LPB would take place from product planning, through circuit design, layout and SI/PI/EMC checking.

LPB is JEITA’s first formal international standard effort. The LPB approach contains five different formats within it, including netlist, geometry, project, component and rule, identified by leading letters (i.e., M-, N-, C-, R-, and G-format). The C- and G- formats are used by CAD/CAE teams, while the N-format is used by system designers.

N-format is netlist, using Verilog. The R-format covers design rules, and is constraint-based, including material characteristics and constraints. G-format covers geometries using XFL, while the C-format covers components, in its own unique language approach. IBIS would fall under the C-format.

Files can be modified throughout life cycle stages by different engineers. This format standardization avoids issues with human error.

The LPB group’s objective is to have an IEEE standard by December 2015.

**CONCLUDING ITEMS**

Lance Wang thanked the co-sponsors, presenters and attendees for their participation and support. The meeting adjourned at 4:30 PM.

**NEXT MEETING**

The next IBIS Open Forum teleconference meeting will be held December 5, 2014.

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**NOTES**

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This meeting was conducted in accordance with ANSI guidance.

The following e-mail addresses are used:

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In the body, for the IBIS Open Forum Reflector:

subscribe ibis <your e-mail address>

In the body, for the IBIS Users' Group Reflector:

subscribe ibis-users <your e-mail address>

Help and other commands:

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[ibis-request@eda.org](mailto:ibis-request@eda-stds.org)

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IBIS Open Forum Reflector ([ibis@eda.org](mailto:ibis@eda-stds.org))

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To obtain general information about IBIS, to ask specific questions for individual response, and to inquire about joining the IBIS Open Forum as a full Member.

[ibis@eda.org](mailto:ibis@eda-stds.org)

To send a message to the general IBIS Open Forum Reflector. This is used mostly for IBIS Standardization business and future IBIS technical enhancements. Job posting information is not permitted.

[ibis-users@eda.org](mailto:ibis-users@eda-stds.org)

To send a message to the IBIS Users' Group Reflector. This is used mostly for IBIS clarification, current modeling issues, and general user concerns. Job posting information is not permitted.

[ibis-bug@eda.org](mailto:ibis-bug@eda-stds.org)

To report ibischk parser BUGs as well as tschk2 parser BUGs. The BUG Report Form for ibischk resides along with reported BUGs at:

<http://www.eda.org/ibis/bugs/ibischk/>

[http://www.eda.org/ibis/bugs/ibischk/bugform.txt](http://www.eda-stds.org/ibis/bugs/ibischk/bugform.txt)

The BUG Report Form for tschk2 resides along with reported BUGs at:

<http://www.eda.org/ibis/tschk_bugs/>

<http://www.eda.org/ibis/tschk_bugs/bugform.txt>

[icm-bug@eda.org](mailto:icm-bug@eda-stds.org)

To report icmchk1 parser BUGs. The BUG Report Form resides along with reported

BUGs at:

[http://www.eda.org/ibis/icm\_bugs/](http://www.eda-stds.org/ibis/icm_bugs/)

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To report s2ibis, s2ibis2 and s2iplt bugs, use the Bug Report Forms which reside at:

[http://www.eda.org/ibis/bugs/s2ibis/bugs2i.txt](http://www.eda-stds.org/ibis/bugs/s2ibis/bugs2i.txt)

[http://www.eda.org/ibis/bugs/s2ibis2/bugs2i2.txt](http://www.eda-stds.org/ibis/bugs/s2ibis2/bugs2i2.txt)

[http://www.eda.org/ibis/bugs/s2iplt/bugsplt.txt](http://www.eda-stds.org/ibis/bugs/s2iplt/bugsplt.txt)

Information on IBIS technical contents, IBIS participants and actual IBIS models are available on the IBIS Home page:

<http://www.eda.org/ibis>

Check the IBIS file directory on eda.org for more information on previous discussions and results:

[http://www.eda.org/ibis/directory.html](http://www.eda-stds.org/ibis/directory.html)

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**IBIS – SAE STANDARDS BALLOT VOTING STATUS**

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **Organization** | **Interest Category** | **Standards Ballot Voting Status** | **October 24, 2014** | **November 14, 2014** | **November 17, 2014** | **November 20, 2014** |
| Altera | Producer | Inactive | X | - | - | - |
| ANSYS | User | Active | - | X | X | X |
| Applied Simulation Technology | User | Inactive | - | - | - | - |
| Cadence Design Systems | User | Active | X | X | X | X |
| Ericsson | Producer | Active | - | X | X | X |
| Huawei Technologies | Producer | Inactive | - | X | - | - |
| Infineon Technologies AG | Producer | Inactive | - | - | - | - |
| Intel Corp. | Producer | Inactive | - | - | X | - |
| IO Methodology | User | Active | X | - | X | X |
| Keysight Technologies (Agilent) | User | Inactive | X | X | - | - |
| LSI (Avago) | Producer | Inactive | - | - | - | - |
| Maxim Integrated Products | Producer | Inactive | - | - | - | - |
| Mentor Graphics | User | Active | X | X | - | X |
| Micron Technology | Producer | Inactive | X | - | - | X |
| Qualcomm | Producer | Inactive | - | - | - | - |
| Signal Integrity Software | User | Inactive | X | - | - | - |
| Synopsys | User | Inactive | X | X | - | - |
| Teraspeed Labs | General Interest | Inactive | X | - | - | - |
| Toshiba | Producer | Inactive | - | - | - | X |
| Xilinx | Producer | Inactive | - | - | - | - |
| ZTE | User | Inactive | - | X | - | - |
| Zuken | User | Inactive | - | - | - | X |

**I/O Buffer Information Specification Committee (IBIS)**

Criteria for Member in good standing:

* Must attend two consecutive meetings to establish voting membership
* Membership dues current
* Must not miss two consecutive Meetings

Interest categories associated with SAE ballot voting are:

* Users - Members that utilize electronic equipment to provide services to an end user.
* Producers - Members that supply electronic equipment.
* General Interest - Members are neither producers nor users. This category includes, but is not limited to, Government, regulatory agencies (state and federal), researchers, other organizations and associations, and/or consumers.